

INCH-POUND

MIL-M-38510/303D

27 January 2003

SUPERSEDING

MIL-M-38510/303C

12 November 1987

## MILITARY SPECIFICATION

### MICROCIRCUITS, DIGITAL, BIPOLAR LOW-POWER SCHOTTKY TTL, NOR GATES, MONOLITHIC SILICON

Inactive for new design after 18 April 1997.

This specification is approved for use by all Departments  
and Agencies of the Department of Defense.

#### 1. SCOPE

1.1 Scope. This specification covers the detail requirements for monolithic silicon, low-power Schottky TTL, positive NOR logic gating microcircuits. Two product assurance classes and a choice of case outlines and lead finishes are provided for each type and are reflected in the complete part number. For this product, the requirements of MIL-M-38510 have been superseded by MIL-PRF-38535, (see 6.3).

1.2 Part number. The part number shall be in accordance with MIL-PRF-38535, and as specified herein.

1.2.1 Device types. The device types shall be as follows:

<u>Device type</u>	<u>Circuit</u>
01	Quadruple, 2-input positive NOR gate
02	Triple, 3-input positive NOR gate
03	Quadruple, 2-input exclusive NOR gate (open collector output)

1.2.2 Device class. The device class shall be the product assurance level as defined in MIL-PRF-38535.

1.2.3 Case outlines. The case outlines shall be as designated in MIL-STD-1835 and as follows:

<u>Outline letter</u>	<u>Descriptive designator</u>	<u>Terminals</u>	<u>Package style</u>
A	GDFP5-F14 or CDFP6-F14	14	Flat pack
B	GDFP4-14	14	Flat pack
C	GDIP1-T14 or CDIP2-T14	14	Dual-in-line
D	GDFP1-F14 or CDFP2-F14	14	Flat pack
X	CQCC2-N20	20	Square leadless chip carrier
2	CQCC1-N20	20	Square leadless chip carrier

Beneficial comments (recommendations, additions, deletions) and any pertinent data which may be of use in improving this document should be addressed to: Commander, Defense Supply Center Columbus, ATTN: DSCC-VAS, 3990 East Broad St., Columbus, OH 43216-5000, by using the self addressed Standardization Document Improvement Proposal (DD Form 1426) appearing at the end of this document or by letter.

AMSC N/A

FSC 5962

DISTRIBUTION STATEMENT A. Approved for public release; distribution is unlimited.

## MIL-M-38510/303D

### 1.3 Absolute maximum ratings.

Supply voltage range .....	-0.5 V dc to +7.0 V dc
Input voltage range .....	-1.5 V dc at -18 mA to +5.5 V dc
Storage temperature range .....	-65° to +150°C
Maximum power dissipation, (P <sub>D</sub> ) <u>1/</u>	
Device type 01 .....	30 mW
Device type 02 .....	38 mW
Device type 03 .....	72 mW
Lead temperature (soldering, 10 seconds) .....	+300°C
Thermal resistance, junction to case (θ <sub>JC</sub> ):	
Cases A, B, C, D, X, and 2 .....	(See MIL-STD-1835)
Junction temperature (T <sub>J</sub> ) <u>2/</u> .....	+175°C

### 1.4 Recommended operating conditions.

Supply voltage (V <sub>CC</sub> ) .....	+4.5 V dc minimum to +5.5 V dc maximum
Minimum high level input voltage (V <sub>IH</sub> ) .....	+2.0 V
Maximum low level input voltage (V <sub>IL</sub> ) .....	+0.7 V
Case operating temperature range (T <sub>C</sub> ) .....	-55° to +125°C

## 2. APPLICABLE DOCUMENTS

### 2.1 Government documents.

2.1.1 Specifications and Standards. The following specifications and standards form a part of this specification to the extent specified herein. Unless otherwise specified, the issues of these documents shall be those listed in the issue of the Departments of Defense Index of Specifications and Standards (DODISS) and supplement thereto, cited in the solicitation.

## SPECIFICATION

### DEPARTMENT OF DEFENSE

MIL-PRF-38535 - Integrated Circuits (Microcircuits) Manufacturing, General Specification for.

## STANDARDS

### DEPARTMENT OF DEFENSE

MIL-STD-883 - Test Method Standard for Microelectronics.  
MIL-STD-1835 - Interface Standard Electronic Component Case Outlines

(Unless otherwise indicated, copies of the above specifications and standards are available from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.2 Order of precedence. In the event of a conflict between the text of this specification and the references cited herein, the text of this document takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

1/ Must withstand the added P<sub>D</sub> due to short-circuit test (e.g., I<sub>OS</sub>).

2/ Maximum junction temperature shall not be exceeded except for allowable short duration burn-in screening condition per method 5004 of MIL-STD-883.

### 3. REQUIREMENTS

3.1 Qualification. Microcircuits furnished under this specification shall be products that are manufactured by a manufacturer authorized by the qualifying activity for listing on the applicable qualified manufacturers list before contract award (see 4.3 and 6.4).

3.2 Item requirements. The individual item requirements shall be in accordance with MIL-PRF-38535 and as specified herein or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein.

3.3 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535 and herein.

3.3.1 Terminal connections. The terminal connections shall be as specified on figure 1.

3.3.2 Truth tables and logic equations. The truth tables and logic equations shall be as specified on figure 2.

3.3.3 Schematic circuits. The schematic circuits shall be maintained by the manufacturer and made available to the qualifying activity and the preparing activity (DSCC-VAS) upon request.

3.3.4 Case outlines. The case outlines shall be as specified in 1.2.3.

3.4 Lead material and finish. The lead material and finish shall be in accordance with MIL-PRF-38535 (see 6.6).

3.5 Electrical performance characteristics. The electrical performance characteristics are as specified in table I, and apply over the full recommended case operating temperature range, unless otherwise specified.

3.6 Electrical test requirements. The electrical test requirements for each device class shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table III.

3.7 Marking. Marking shall be in accordance with MIL-PRF-38535.

3.8 Microcircuit group assignment. The devices covered by this specification shall be in microcircuit group number 8 (see MIL-PRF-38535, appendix A).

### 4. VERIFICATION

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with MIL-PRF-38535 or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not effect the form, fit, or function as described herein.

4.2 Screening. Screening shall be in accordance with, MIL-PRF-38535 and shall be conducted on all devices prior to qualification and quality conformance inspection. The following additional criteria shall apply:

- a. The burn-in test duration, test condition, and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The burn-in test circuit shall be maintained under document control by the device manufacturer's Technology Review Board (TRB) in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015 of MIL-STD-883.
- b. Interim and final electrical test parameters shall be as specified in table II, except interim electrical parameters test prior to burn-in is optional at the discretion of the manufacturer.
- c. Additional screening for space level product shall be as specified in MIL-PRF-38535.

TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions <sup>1/</sup> -55°C ≤ T <sub>C</sub> ≤ +125°C	Device types	Limits		Unit
				Min	Max	
High level output voltage	V <sub>OH</sub>	V <sub>CC</sub> = +4.5 V, V <sub>IN</sub> = +0.7 V, I <sub>OH</sub> = -400 μA	01, 02	+2.5		V
Low level output voltage	V <sub>OL</sub>	V <sub>CC</sub> = +4.5 V, I <sub>OL</sub> = +4 mA; V <sub>IN</sub> = +2.0 V	All		+0.4	V
High level input current	I <sub>IH1</sub>	V <sub>CC</sub> = +5.5 V, V <sub>IN</sub> = +2.7 V	01, 02		+20	μA
			03		+40	
	I <sub>IH2</sub>	V <sub>CC</sub> = +5.5 V, V <sub>IN</sub> = +5.5 V	01, 02		+100	μA
			03		+200	
Collector cut-off current	I <sub>CEX</sub>	V <sub>CC</sub> = +4.5 V, V <sub>IN</sub> = +0.7 V, V <sub>OH</sub> = +5.5 V	03		+100	μA
Low level input current	I <sub>IL</sub>	V <sub>CC</sub> = +5.5 V, V <sub>IN</sub> = +0.4 V	01	0	-400	μA
			02	-30	-400	
			03	-200	-760	
Short circuit output current	I <sub>OS</sub>	V <sub>CC</sub> = +5.5 V <sup>2/</sup> , V <sub>IN</sub> = 0 V	01, 02	-15	-130	mA
Input clamp voltage	V <sub>IC</sub>	V <sub>CC</sub> = +4.5 V, I <sub>IN</sub> = -18 mA, T <sub>C</sub> = +25°C	All		-1.5	V
High level supply current	I <sub>CCH</sub>	V <sub>CC</sub> = +5.5 V, V <sub>IN</sub> = 0 V	01		+3.2	mA
			02		+4.0	
Low level supply current	I <sub>CCL</sub>	V <sub>CC</sub> = +5.5 V, V <sub>IN</sub> = +4.5 V	01		+5.4	mA
			02		+6.8	
Supply current	I <sub>CC</sub>	V <sub>CC</sub> = +5.5 V <sup>3/</sup>	03		+13	mA
Propagation delay time high-to-low level	t <sub>PHL</sub>	C <sub>L</sub> = 50 pF ± 10%, R <sub>L</sub> = 2 kΩ ± 5%, V <sub>CC</sub> = +5.0 V	01	2	30	ns
			02	2	26	
	t <sub>PHL1</sub>	From A or B Other input low	03	2	45	
	t <sub>PHL2</sub>	From A or B Other input high		2	45	
Propagation delay time low-to-high level	t <sub>PLH</sub>	C <sub>L</sub> = 50 pF ± 10%, R <sub>L</sub> = 2 kΩ ± 5%, V <sub>CC</sub> = +5.0 V	01, 02	2	30	ns
	t <sub>PLH1</sub>	From A or B Other input low	03	2	56	
	t <sub>PLH2</sub>	From A or B Other input high		2	56	

1/ Complete terminal conditions shall be as specified in table III.

2/ Not more than one output should be shorted at a time.

3/ I<sub>CC</sub> is measured with one input of each gate at +4.5 V, the other inputs grounded, and the outputs open.

TABLE II. Electrical test requirements.

MIL-PRF-38535 test requirements	Subgroups (see table III)	
	Class S devices	Class B devices
Interim electrical parameters	1	1
Final electrical test parameters	1*, 2, 3, 9, 10, 11	1*, 2, 3, 9
Group A test requirements	1, 2, 3, 9, 10, 11	1, 2, 3, 9, 10, 11
Group C end-point electrical parameters	1, 2, 3, 9, 10, 11	1, 2, 3
Group D end-point electrical parameters	1, 2, 3	1, 2, 3

\*PDA applies to subgroup 1.

4.3 Qualification inspection. Qualification inspection shall be in accordance with MIL-PRF-38535.

4.4 Technology Conformance inspection (TCI). Technology conformance inspection shall be in accordance with MIL-PRF-38535 and herein for groups A, B, C, and D inspections (see 4.4.1 through 4.4.4).

4.4.1 Group A inspection. Group A inspection shall be in accordance with table III of MIL-PRF-38535 and as follows:

- a. Tests shall be as specified in table II herein.
- b. Subgroups 4, 5, 6, 7, and 8 shall be omitted.

4.4.2 Group B inspection. Group B inspection shall be in accordance with table II of MIL-PRF-38535.

4.4.3 Group C inspection. Group C inspection shall be in accordance with table IV of MIL-PRF-38535 and as follows:

- a. End-point electrical parameters shall be as specified in table II herein.
- b. The steady-state life test duration, test condition, and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The burn-in test circuit shall be maintained under document control by the device manufacturer's Technology Review Board (TRB) in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1005 of MIL-STD-883.

4.4.4 Group D inspection. Group D inspection shall be in accordance with table V of MIL-PRF-38535. End-point electrical parameters shall be as specified in table II herein.

4.5 Methods of inspection. Methods of inspection shall be specified and as follows.

4.5.1 Voltage and current. All voltages given are referenced to the microcircuit ground terminal. Currents given are conventional and positive when flowing into the referenced terminal.

Terminal number	Terminal symbol device type 01		Terminal symbol device type 02		Terminal symbol device type 03	
	Cases 2 and X	Cases A, B, C, D	Cases 2 and X	Cases A, B, C, D	Cases 2 and X	Cases A, B, C, D
1	NC	1Y	NC	1A	NC	1A
2	1Y	1A	1A	1B	1A	1B
3	1A	1B	1B	2A	1B	1Y
4	1B	2Y	2A	2B	1Y	2Y
5	NC	2A	NC	2C	NC	2A
6	2Y	2B	2B	2Y	2Y	2B
7	NC	GND	NC	GND	NC	GND
8	2A	3A	2C	3Y	2A	3A
9	2B	3B	2Y	3A	2B	3B
10	GND	3Y	GND	3B	GND	3Y
11	NC	4A	NC	3C	NC	4Y
12	3A	4B	3Y	1Y	3A	4A
13	3B	4Y	3A	1C	3B	4B
14	3Y	V <sub>CC</sub>	3B	V <sub>CC</sub>	3Y	V <sub>CC</sub>
15	NC		NC		NC	
16	4A		3C		4Y	
17	NC		NC		NC	
18	4B		1Y		4A	
19	4Y		1C		4B	
20	V <sub>CC</sub>		V <sub>CC</sub>		V <sub>CC</sub>	

FIGURE 1. Terminal connections.

Device type 01

Truth table each gate		
Input		Output
A	B	Y
H	X	L
X	H	L
L	L	H

X = Irrelevant

Positive logic:  $Y = \overline{A + B}$

Device type 02

Truth table each gate			
Input			Output
A	B	C	Y
H	X	X	L
X	H	X	L
X	X	H	L
L	L	L	H

X = Irrelevant

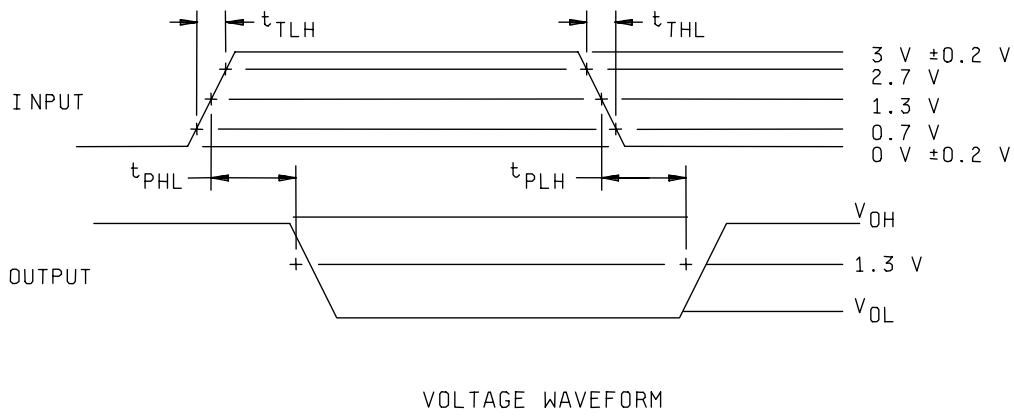
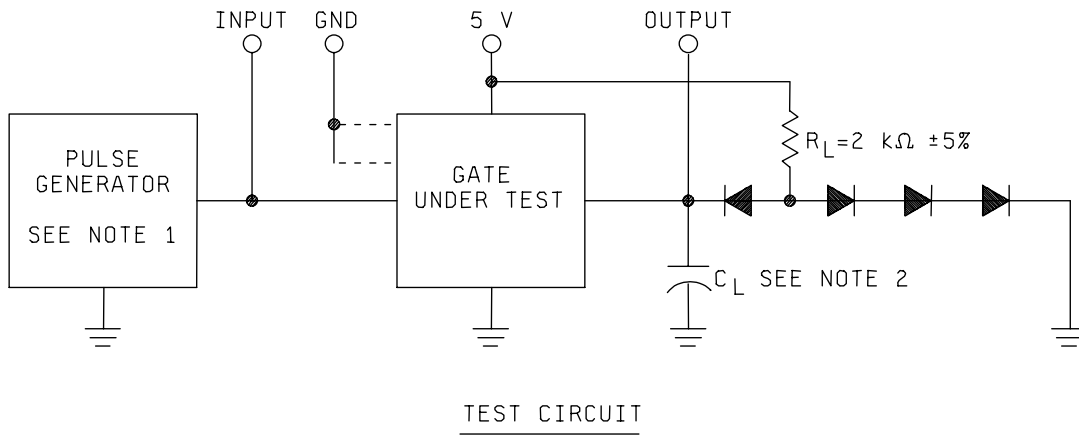
Positive logic:  $Y = \overline{A + B + C}$

Device types 03

Truth table each gate		
Input		Output
A	B	Y
L	L	H
L	H	L
H	L	L
H	H	H

Positive logic:  $Y = \overline{A \oplus B} = AB + \overline{A} \overline{B}$

FIGURE 2. Truth tables and logic equations.

Device type 01 and 02

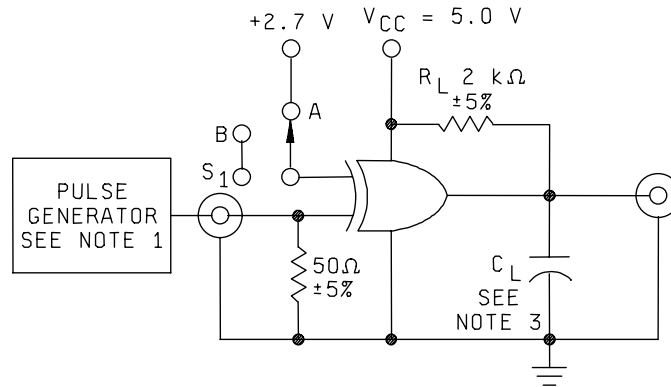
## NOTES:

1. The pulse generator has the following characteristics:  $t_{THL} \leq 6 \text{ ns}$ ,  $t_{TLH} \leq 15 \text{ ns}$ ,  $PRR \leq 1 \text{ MHz}$ ,  $t_p = .5 \mu\text{s}$ , and  $Z_{OUT} \cong 50 \Omega$ .
2.  $C_L = 50 \text{ pF} \pm 10\%$ , including scope probe, wiring, and stray capacitance, without package in test fixture.
3. Voltage measurements are to be made with respect to network ground terminal.
4. All diodes are 1N3064 or equivalent.

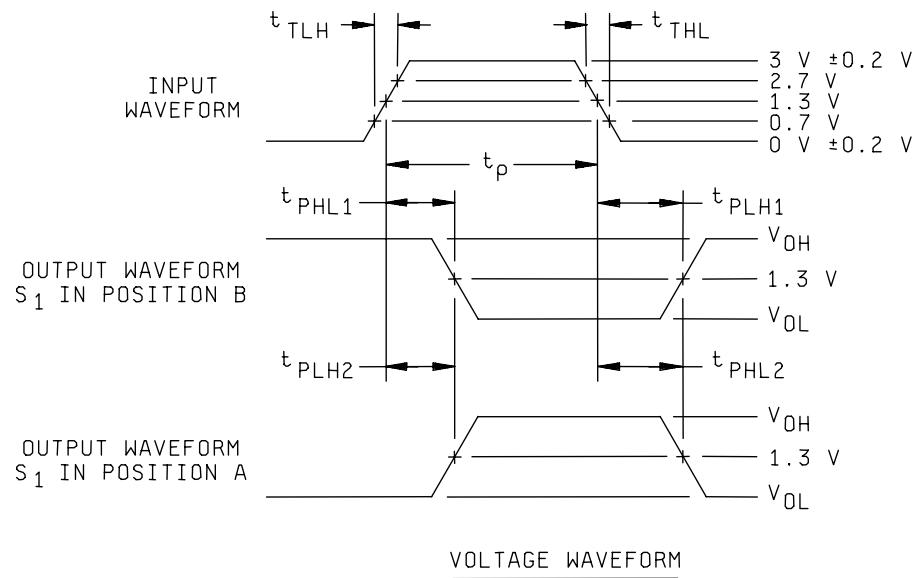
FIGURE 3. Switching time test circuit and waveforms for device types 01 through 03.



## DEVICE TYPE 03



TEST CIRCUIT



## NOTES:

1. The pulse generator has the following characteristics:  $t_{THL} \leq 6 \text{ ns}$ ,  $t_{TLH} \leq 15 \text{ ns}$ ,  $\text{PRR} \leq 1 \text{ MHz}$ ,  $t_p = .5 \mu\text{s}$ , and  $Z_{OUT} \cong 50 \Omega$ .
2.  $C_L = 50 \text{ pF} \pm 10\%$ , including scope probe, wiring, and stray capacitance, without package in test fixture.
3. Voltage measurements are to be made with respect to network ground terminal.
4. All diodes are 1N3064 or equivalent.

FIGURE 3. Switching time test circuit and waveforms for device types 01 through 03 - Continued.

TABLE III. Group A inspection for device type 01.  
Terminal conditions (pins not designated may be high  $\geq 2.0$  V, low  $\leq 0.7$  V, or open).

Subgroup	Symbol	MIL-STD-883 method	Cases A,B,C,D	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured terminal	Limits		Unit
			Cases X, 2 1/	2	3	4	6	8	9	10	12	13	14	16	18	19	20				
			Test no.	1Y	1A	1B	2Y	2A	2B	GND	3A	3B	3Y	4A	4B	4Y	V <sub>CC</sub>		Min	Max	
1 T <sub>c</sub> = 25°C	V <sub>OH</sub>	3006	1	-400 $\mu$ A	0.7 V	0.7 V		5.5 V	5.5 V	GND	5.5 V	5.5 V		5.5 V	5.5 V		4.5 V	1Y	2.5		V
			2		5.5 V	5.5 V	-400 $\mu$ A	0.7 V	0.7 V		5.5 V	5.5 V						2Y			
			3					5.5 V	5.5 V		0.7 V	0.7 V	-400 $\mu$ A					3Y			
			4					5.5 V	5.5 V		5.5 V	5.5 V		0.7 V	0.7 V	-400 $\mu$ A		4Y			
	V <sub>OL</sub>	3007	5	4 mA	2.0 V	GND		GND	GND		GND	GND		GND	GND			1Y		0.4	
			6	4 mA	GND	2.0 V		GND										1Y			
			7			GND	4 mA	2.0 V										2Y			
			8				4 mA	GND	2.0 V									2Y			
			9						GND		2.0 V		4 mA					3Y			
			10								GND	2.0 V	4 mA					3Y			
			11									GND		2.0 V		4 mA		4Y			
			12															4Y			
			13		- 18 mA													1A		-1.5	
			14			- 18 mA												1B			
			15					- 18 mA										2A			
			16						- 18 mA									2B			
			17								- 18 mA							3A			
			18									- 18 mA						3B			
			19											- 18 mA				4A			
			20												- 18 mA			4B			
	I <sub>IH1</sub>	3010	21		2.7 V	GND		GND	GND		GND	GND		GND	GND		5.5 V	1A		20	$\mu$ A
			22		GND	2.7 V		GND										1B			
			23			GND		2.7 V										2A			
			24					GND	2.7 V									2B			
			25						GND		2.7 V							3A			
			26								GND	2.7 V						3B			
			27									GND		2.7 V				4A			
			28											GND	2.7 V			4B			
	I <sub>IH2</sub>		29		5.5 V										GND			1A		100	
			30		GND	5.5 V												1B			
			31			GND		5.5 V										2A			
			32					GND	5.5 V									2B			
			33						GND		5.5 V							3A			
			34								GND	5.5 V						3B			
			35									GND		5.5 V				4A			
			36									GND			5.5 V			4B			
	I <sub>IL</sub> 2/	3009	37		0.4 V	5.5 V		5.5 V	5.5 V		5.5 V	5.5 V		5.5 V				1A	2/	2/	
			38		5.5 V	0.4 V		5.5 V										1B			
			39			5.5 V		0.4 V										2A			
			40					5.5 V	0.4 V									2B			
			41						5.5 V		0.4 V							3A			
			42								5.5 V	0.4 V						3B			
			43									5.5 V		0.4 V				4A			
			44									5.5 V		5.5 V	0.4 V			4B			
	I <sub>OS</sub> 3/	3011	45	GND	GND	GND												1Y	3/	3/	mA
			46				GND	GND	GND									2Y			
			47								GND	GND	GND					3Y			
			48											GND	GND	GND		4Y			

See footnotes at end of device type 01

TABLE III. Group A inspection for device type 01 – Continued.  
Terminal conditions (pins not designated may be high  $\geq 2.0$  V, low  $\leq 0.7$  V, or open).

Subgroup	Symbol	MIL-STD-883 method	Cases A,B,C,D	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured terminal	Limits		Unit
			Cases X, 2 1/	2	3	4	6	8	9	10	12	13	14	16	18	19	20				
			Test no.	1Y	1A	1B	2Y	2A	2B	GND	3A	3B	3Y	4A	4B	4Y	V <sub>CC</sub>		Min	Max	
1	I <sub>CCH</sub>	3005	49		GND	GND		GND	GND	GND	GND	GND		GND	GND		5.5 V	V <sub>CC</sub>		3.2	mA
T <sub>C</sub> = 25°C	I <sub>CCL</sub>	3005	50		4.5 V	4.5 V		4.5 V	4.5 V	GND	4.5 V	4.5 V		4.5 V	4.5 V		5.5 V	V <sub>CC</sub>		5.4	mA
2	Same tests, terminal conditions and limits as for subgroup 1, except T <sub>C</sub> = +125°C and V <sub>IC</sub> tests are omitted.																				
3	Same tests, terminal conditions and limits as for subgroup 1, except T <sub>C</sub> = -55°C and V <sub>IC</sub> tests are omitted.																				
9 T <sub>C</sub> = 25°C	t <sub>PHL</sub>	3003 Fig. 3	51	OUT	IN	GND				GND							5.0 V	1A to 1Y	2	16	ns
			52	OUT	GND	IN				"						"	1B to 1Y	"	"	"	
			53				OUT	IN	GND	"						"	2A to 2Y	"	"	"	
			54				OUT	GND	IN	"						"	2B to 2Y	"	"	"	
			55							"	IN	GND	OUT			"	3A to 3Y	"	"	"	
			56							"	GND	IN	OUT			"	3B to 3Y	"	"	"	
			57							"				IN	GND	OUT	"	4A to 4Y	"	"	"
			58							"				GND	IN	OUT	"	4B to 4Y	"	"	"
	t <sub>PLH</sub>	"	59	OUT	IN	GND				"						"	1A to 1Y	"	22	"	
			60	OUT	GND	IN				"						"	1B to 1Y	"	"	"	
			61				OUT	IN	GND	"						"	2A to 2Y	"	"	"	
			62				OUT	GND	IN	"						"	2B to 2Y	"	"	"	
			63							"	IN	GND	OUT			"	3A to 3Y	"	"	"	
			64							"	GND	IN	OUT			"	3B to 3Y	"	"	"	
			65							"				IN	GND	OUT	"	4A to 4Y	"	"	"
			66							"				GND	IN	OUT	"	4B to 4Y	"	"	"
10 T <sub>C</sub> = 125°C	t <sub>PHL</sub>	"	67	OUT	IN	GND				"							"	1A to 1Y	"	26	"
			68	OUT	GND	IN				"						"	1B to 1Y	"	"	"	
			69				OUT	IN	GND	"						"	2A to 2Y	"	"	"	
			70				OUT	GND	IN	"						"	2B to 2Y	"	"	"	
			71							"	IN	GND	OUT			"	3A to 3Y	"	"	"	
			72							"	GND	IN	OUT			"	3B to 3Y	"	"	"	
			73							"				IN	GND	OUT	"	4A to 4Y	"	"	"
			74							"				GND	IN	OUT	"	4B to 4Y	"	"	"
	t <sub>PLH</sub>	"	75	OUT	IN	GND				"						"	1A to 1Y	"	30	"	
			76	OUT	GND	IN				"						"	1B to 1Y	"	"	"	
			77				OUT	IN	GND	"						"	2A to 2Y	"	"	"	
			78				OUT	GND	IN	"						"	2B to 2Y	"	"	"	
			79							"	IN	GND	OUT			"	3A to 3Y	"	"	"	
			80							"	GND	IN	OUT			"	3B to 3Y	"	"	"	
			81							"				IN	GND	OUT	"	4A to 4Y	"	"	"
			82							"				GND	IN	OUT	"	4B to 4Y	"	"	"
11	Same tests, terminal conditions and limits as for subgroup 10, except T <sub>C</sub> = -55° C.																				

1/ For cases X and 2, pins not referenced are NC.

2/ I<sub>IL</sub> limits in  $\mu$ A shall be as follows:

Parameters	Circuits						
	A	B	C	D	E	F	G
I <sub>IL</sub>	-0/-360	-30/-300	-160/-400	-120/-360	-150/-380	-100/-340	-160/-400

3/ I<sub>OS</sub> limits for circuits A, B, C, D, E, and F are -15/-100 mA; for circuit G, -30/-130 mA.

TABLE III. Group A inspection for device type 02.  
Terminal conditions (pins not designated may be high  $\geq 2.0$  V, low  $\leq 0.7$  V, or open).

Subgroup	Symbol	MIL-STD-883 method	Cases A,B,C,D	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured terminal	Limits		Unit	
			Cases X, 2 1/	2	3	4	6	8	9	10	12	13	14	16	18	19	20					
			Test no.	1A	1B	2A	2B	2C	2Y	GND	3Y	3A	3B	3C	1Y	1C	V <sub>CC</sub>		Min	Max		
1 T <sub>C</sub> = 25°C	V <sub>OH</sub>	3007	"	1	0.7 V	0.7 V	5.5 V	5.5 V	5.5 V									1Y	2.5		V	
			"	2	5.5 V	5.5 V	0.7 V	0.7 V	0.7 V	-400 μA	"		5.5 V	5.5 V	5.5 V		5.5 V	"	2Y	"	"	
			"	3	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V		"	-400 μA	0.7 V	0.7 V	0.7 V		5.5 V	"	3Y	"	"	
	V <sub>OL</sub>	3007	"	4	2.0 V	GND	GND	GND	GND		"		GND	GND	GND	4 mA	GND	"	1Y		0.4	"
			"	5	GND	2.0 V	"	"	"		"		"	"	"	"	GND	"	1Y		"	"
			"	6	"	GND	"	"	"		"		"	"	"	"	2.0 V	"	1Y	"	"	"
			"	7	"	"	2.0 V	"	"	4 mA	"		"	"	"	"	GND	"	2Y	"	"	"
			"	8	"	"	GND	2.0 V	"	"	"		"	"	"	"	"	"	2Y	"	"	"
			"	9	"	"	"	GND	2.0 V	"	"		"	"	"	"	"	"	2Y	"	"	"
			"	10	"	"	"	"	GND		"	4 mA	2.0 V	"	"	"	"	"	3Y	"	"	"
			"	11	"	"	"	"	"		"	"	GND	2.0 V		"	"	"	3Y	"	"	"
			"	12	"	"	"	"	"		"	"	GND	2.0 V	2.0 V		"	"	3Y	"	"	"
	V <sub>IC</sub>		"	13	-18mA						"							"	1A	-1.5	"	
			"	14		-18mA					"							"	1B	"	"	
			"	15			-18mA				"							"	2A	"	"	
			"	16				-18mA			"							"	2B	"	"	
			"	17					-18mA		"							"	2C	"	"	
			"	18							"		-18mA					"	3A	"	"	
			"	19							"			-18mA				"	3B	"	"	
			"	20							"				-18mA			"	3C	"	"	
			"	21							"						-18mA	"	1C	"	"	
	I <sub>IH1</sub>	3010	"	22	2.7 V	GND	GND	GND	GND		"		GND	GND	GND		GND	5.5 V	1A	20	μA	
			"	23	GND	2.7 V	GND	"	"	"		"	"	"	"	"	"	"	1B	"	"	
			"	24	"	GND	2.7 V	"	"	"		"	"	"	"	"	"	"	2A	"	"	
			"	25	"	"	GND	2.7 V	"	"		"	"	"	"	"	"	"	2B	"	"	
			"	26	"	"	"	GND	2.7 V	"		"	"	"	"	"	"	"	2C	"	"	
			"	27	"	"	"	"	GND	"		2.7 V	"	"	"	"	"	"	3A	"	"	
			"	28	"	"	"	"	"	"		GND	2.7 V	"	"	"	"	"	3B	"	"	
			"	29	"	"	"	"	"	"		"	GND	2.7 V	2.7 V	"	"	"	3C	"	"	
			"	30	"	"	"	"	"	"		"	"	GND		2.7 V	"	1C	"	"		
	I <sub>IH2</sub>		"	31	5.5 V	"	"	"	"	"		"	"	"	"		GND	"	1A	100	"	
			"	32	GND	5.5 V	"	"	"	"		"	"	"	"		"	"	1B	"	"	
			"	33	"	GND	5.5 V	"	"	"		"	"	"	"		"	"	2A	"	"	
			"	34	"	"	GND	5.5 V	"	"		"	"	"	"		"	"	2B	"	"	
			"	35	"	"	"	GND	5.5 V	"		"	"	"	"		"	"	2C	"	"	
			"	36	"	"	"	"	GND	"		5.5 V	"	"	"		"	"	3A	"	"	
			"	37	"	"	"	"	"	"		GND	5.5 V	"	"		"	"	3B	"	"	
			"	38	"	"	"	"	"	"		"	GND	5.5 V		"	"	"	3C	"	"	
			"	39	"	"	"	"	"	"		"	"	GND		5.5 V	"	1C	"	"		
	I <sub>IL 2/</sub>	3009	"	40	0.4 V	5.5 V	5.5 V	5.5 V	5.5 V		"		5.5 V	5.5 V	5.5 V		"	"	1A	2/	2/	"
			"	41	5.5 V	0.4 V	5.5 V	"	"		"		"	"	"		"	"	1B	"	"	"
			"	42	"	5.5 V	0.4 V	"	"		"		"	"	"		"	"	2A	"	"	"
			"	43	"	"	5.5 V	0.4 V	"		"		"	"	"		"	"	2B	"	"	"
			"	44	"	"	"	5.5 V	0.4 V	"		"	"	"	"		"	"	2C	"	"	"
			"	45	"	"	"	"	5.5 V	"		"		0.4 V	"		"	"	3A	"	"	"
			"	46	"	"	"	"	"		"		5.5 V	0.4 V		5.5 V	"	3B	"	"	"	
			"	47	"	"	"	"	"		"		"	5.5 V	0.4 V	5.5 V	"	3C	"	"	"	
			"	48	"	"	"	"	"		"		"	"	5.5 V	0.4 V	"	1C	"	"	"	

See footnotes at end of device type 02

TABLE III. Group A inspection for device type 02 – Continued.  
Terminal conditions (pins not designated may be high  $\geq 2.0$  V, low  $\leq 0.7$  V, or open).

Subgroup	Symbol	MIL-STD-883 method	Cases A,B,C,D	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured terminal	Limits		Unit	
			Cases X, 2 1/	2	3	4	6	8	9	10	12	13	14	16	18	19	20		Min	Max		
			Test no.	1A	1B	2A	2B	2C	2Y	GND	3Y	3A	3B	3C	1Y	1C	V <sub>CC</sub>					
1 T <sub>C</sub> = 25°C	I <sub>OS</sub> 3/	3011	49	GND	GND					"					GND	GND	5.5 V	1Y	3/	3/	mA	
		"	50			GND	GND	GND	GND	"							"	2Y	"	"	"	
		"	51							"	GND	GND	GND	GND			"	3Y	"	"	"	
	I <sub>CC</sub> H	3005	52	GND	GND	GND	GND	GND		GND		GND	GND	GND		GND	"	V <sub>CC</sub>		4.0	mA	
I <sub>CC</sub> L	3005	53	4.5 V	4.5 V	4.5 V	4.5 V	4.5 V		GND		4.5 V	4.5 V	4.5 V		4.5 V	"	V <sub>CC</sub>		6.8	mA		
2	Same tests, terminal conditions and limits as for subgroup 1, except T <sub>C</sub> = +125° C, and V <sub>IC</sub> tests are omitted.																					
3	Same tests, terminal conditions and limits as for subgroup 1, except T <sub>C</sub> = -55° C, and V <sub>IC</sub> tests are omitted.																					
9 T <sub>C</sub> = 25°C	t <sub>PHL</sub>	3003 (Fig. 3)	54	IN	GND					GND					OUT	GND	5.0 V	1A to 1Y	2	16	ns	
			55	GND	IN						"					"	GND	"	1B to 1Y	"	"	"
			56	GND	GND						"					"	IN	"	1C to 1Y	"	"	"
			57			IN	GND	GND	OUT	"								"	2A to 2Y	"	"	"
			58			GND	IN	GND	"	"							"	2B to 2Y	"	"	"	
			59			GND	GND	IN	"	"							"	2C to 2Y	"	"	"	
			60							"	OUT	IN	GND	GND			"	3A to 3Y	"	"	"	
			61							"	"	GND	IN	GND			"	3B to 3Y	"	"	"	
			62							"	"	GND	GND	IN			"	3C to 3Y	"	"	"	
	t <sub>PLH</sub>	"	63	IN	GND					"						OUT	GND	"	1A to 1Y	"	22	ns
			64	GND	IN					"						"	GND	"	1B to 1Y	"	"	"
			65	GND	GND					"						"	IN	"	1C to 1Y	"	"	"
			66			IN	GND	GND	OUT	"							"	2A to 2Y	"	"	"	
			67			GND	IN	GND	"	"							"	2B to 2Y	"	"	"	
			68			GND	GND	IN	"	"							"	2C to 2Y	"	"	"	
			69							"	OUT	IN	GND	GND			"	3A to 3Y	"	"	"	
			70							"	"	GND	IN	GND			"	3B to 3Y	"	"	"	
			71							"	"	GND	GND	IN			"	3C to 3Y	"	"	"	
10 T <sub>C</sub> = 125°C	t <sub>PHL</sub>	"	72	IN	GND					"					OUT	GND	"	1A to 1Y	"	26	ns	
			73	GND	IN					"						"	GND	"	1B to 1Y	"	"	"
			74	GND	GND					"						"	IN	"	1C to 1Y	"	"	"
			75			IN	GND	GND	OUT	"							"	2A to 2Y	"	"	"	
			76			GND	IN	GND	"	"							"	2B to 2Y	"	"	"	
			77			GND	GND	IN	"	"							"	2C to 2Y	"	"	"	
			78							"	OUT	IN	GND	GND			"	3A to 3Y	"	"	"	
			79							"	"	GND	IN	GND			"	3B to 3Y	"	"	"	
			80							"	"	GND	GND	IN			"	3C to 3Y	"	"	"	
	t <sub>PLH</sub>	"	81	IN	GND					"						OUT	GND	"	1A to 1Y	"	30	ns
			82	GND	IN					"						"	GND	"	1B to 1Y	"	"	"
			83	GND	GND					"						"	IN	"	1C to 1Y	"	"	"
			84			IN	GND	GND	OUT	"							"	2A to 2Y	"	"	"	
			85			GND	IN	GND	"	"							"	2B to 2Y	"	"	"	
			86			GND	GND	IN	"	"							"	2C to 2Y	"	"	"	
			87							"	OUT	IN	GND	GND			"	3A to 3Y	"	"	"	
			88							"	"	GND	IN	GND			"	3B to 3Y	"	"	"	
			89							"	"	GND	GND	IN			"	3C to 3Y	"	"	"	
11	Same tests, terminal conditions and limits as for subgroup 10, except T <sub>C</sub> = -55° C.																					

TABLE III. Group A inspection for device type 02 – Continued.  
Terminal conditions (pins not designated may be high  $\geq 2.0$  V, low  $\leq 0.7$  V, or open).

1/ For cases X and 2, pins not referenced are NC.

2/  $I_{IL}$  limits in  $\mu A$  shall be as follows:

Parameters	Circuits						
	A	B	C	D	E	F	G
$I_{IL}$	-120/-360	-30/-300	-160/-400	-120/-360	-100/-340	-160/-400	-150/-380

3/  $I_{OS}$  limits for circuits A, B, C, D, E, and F are -15/-100 mA; for circuit G, -30/-130 mA.

TABLE III. Group A inspection for device type 03.  
Terminal conditions (pins not designated may be high  $\geq 2.0$  V, low  $\leq 0.7$  V, or open).

Subgroup	Symbol	MIL-STD-883 method	Cases A,B,C,D	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured terminal	Limits		Unit
			Cases X, 2 1/	2	3	4	6	8	9	10	12	13	14	16	18	19	20				
			Test no.	1A	1B	1Y	2Y	2A	2B	GND	3A	3B	3Y	4Y	4A	4B	V <sub>CC</sub>		Min	Max	
1 T <sub>c</sub> = 25°C	V <sub>OL</sub>	3007	1	0.7 V	2.0 V	4 mA		5.5 V	5.5 V	GND	5.5 V	5.5 V			5.5 V	5.5 V	4.5 V	1Y		0.4	V
		"	2	2.0 V	0.7 V	4 mA		5.5 V	5.5 V	"	"	"			"	"	"	1Y		"	"
		"	3	5.5 V	5.5 V		4 mA	0.7 V	2.0 V	"	"	"			"	"	"	2Y		"	"
		"	4	"	"		4 mA	2.0 V	0.7 V	"	"	"			"	"	"	2Y		"	"
		"	5	"	"			5.5 V	5.5 V	"	0.7 V	2.0 V	4 mA		"	"	"	3Y		"	"
		"	6	"	"					"	2.0 V	0.7 V	4 mA		"	"	"	3Y		"	"
		"	7	"	"			"	"	"	5.5 V	5.5 V		4 mA	0.7 V	2.0 V	"	4Y		"	"
		"	8	"	"			"	"	"	"	"		4 mA	2.0 V	0.7 V	"	4Y		"	"
	I <sub>CEX</sub>		9	0.7 V	0.7 V	5.5 V		"	"	"	"	"			5.5 V	5.5 V	"	1Y		100	μA
			10	2.0 V	2.0 V	5.5 V		"	"	"	"	"			"	"	"	1Y		"	"
			11	5.5 V	5.5 V		5.5 V	0.7 V	0.7 V	"	"	"			"	"	"	2Y		"	"
			12	"	"		5.5 V	2.0 V	2.0 V	"	"	"			"	"	"	2Y		"	"
			13	"	"			5.5 V	5.5 V	"	0.7 V	0.7 V	5.5 V		"	"	"	3Y		"	"
			14	"	"			"	"	"	2.0 V	2.0 V	5.5 V		"	"	"	3Y		"	"
			15	"	"			"	"	"	5.5 V	5.5 V		5.5 V	0.7 V	0.7 V	"	4Y		"	"
			16	"	"			"	"	"	5.5 V	5.5 V		5.5 V	2.0 V	2.0 V	"	4Y		"	"
	V <sub>IC</sub>		17	-18 mA						"							"	1A		-1.5	V
			18		-18 mA					"							"	1B		"	"
			19					-18 mA		"							"	2A		"	"
			20						-18 mA	"							"	2B		"	"
			21							"	-18 mA						"	3A		"	"
			22							"		-18 mA					"	3B		"	"
			23							"					-18 mA		"	4A		"	"
			24							"						-18 mA	"	4B		"	"
	I <sub>IH1</sub>	3010	25	2.7 V	GND			GND	GND	"	GND	GND			GND	GND	5.5 V	1A		40	μA
		"	26	GND	2.7 V			GND	"	"	"	"			"	"	"	1B		"	"
		"	27		GND			2.7 V	"	"	"	"			"	"	"	2A		"	"
		"	28	"	"			GND	2.7 V	"	"	"			"	"	"	2B		"	"
		"	29	"	"			"	GND	"	2.7 V	"			"	"	"	3A		"	"
		"	30	"	"			"	"	"	GND	2.7 V			"	"	"	3B		"	"
		"	31	"	"			"	"	"	"	GND			2.7 V	"	"	4A		"	"
		"	32	"	"			"	"	"	"	"			GND	2.7 V	"	4B		"	"
	I <sub>IH2</sub>	"	33	5.5 V	"			"	"	"	"	"			"	GND	"	1A		200	"
		"	34	GND	5.5 V			"	"	"	"	"			"	"	"	1B		"	"
		"	35	"	GND			5.5 V	"	"	"	"			"	"	"	2A		"	"
		"	36	"	"			GND	5.5 V	"	"	"			"	"	"	2B		"	"
		"	37	"	"			"	GND	"	5.5 V	"			"	"	"	3A		"	"
		"	38	"	"			"	"	"	GND	5.5 V			"	"	"	3B		"	"
		"	39	"	"			"	"	"	"	GND			5.5 V	"	"	4A		"	"
		"	40	"	"			"	"	"	"	GND			GND	5.5 V	"	4B		"	"
	I <sub>IL</sub> 2/	3009	41	0.4 V	5.5 V			5.5 V	5.5 V	"	5.5 V	5.5 V			5.5 V	"	"	1A	2/	2/	"
		"	42	5.5 V	0.4 V			5.5 V	"	"	"	"			"	"	"	1B	"	"	"
		"	43	"	5.5 V			0.4 V	"	"	"	"			"	"	"	2A	"	"	"
		"	44	"	"			5.5 V	0.4 V	"	"	"			"	"	"	2B	"	"	"
		"	45	"	"			"	5.5 V	"	0.4 V	"			"	"	"	3A	"	"	"
		"	46	"	"			"	"	"	5.5 V	0.4 V			"	"	"	3B	"	"	"
		"	47	"	"			"	"	"	"	5.5 V			0.4 V	"	"	4A		"	"
		"	48	"	"			"	"	"	"	5.5 V			5.5 V	0.4 V	"	4B	"	"	"

See footnotes at end of device type 03.

TABLE III. Group A inspection for device type 03 – Continued.  
Terminal conditions (pins not designated may be high  $\geq 2.0$  V, low  $\leq 0.7$  V, or open).

Subgroup	Symbol	MIL-STD-883 method	Cases A,B,C,D	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured terminal	Limits		Unit
			Cases X, 2 1/	2	3	4	6	8	9	10	12	13	14	16	18	19	20				
			Test no.	1A	1B	1Y	2Y	2A	2B	GND	3A	3B	3Y	4Y	4A	4B	V <sub>CC</sub>		Min	Max	
1 T <sub>C</sub> = 25°C	I <sub>CC</sub>	3005	49	GND	4.5 V			GND	4.5 V	GND	GND	4.5 V			GND	4.5 V	5.5 V	V <sub>CC</sub>		13	mA
2	Same tests, terminal conditions and limits as for subgroup 1, except T <sub>C</sub> = +125° C, and V <sub>I C</sub> tests are omitted.																				
3	Same tests, terminal conditions and limits as for subgroup 1, except T <sub>C</sub> = -55° C, and V <sub>I C</sub> tests are omitted.																				
9 T <sub>C</sub> = 25°C	t <sub>PHL 1</sub>	3003 (Fig. 3)	50	IN	GND	OUT				GND							5.0 V	1A to 1Y	2	40	ns
			51	GND	IN	OUT				"							"	1B to 1Y	"	"	"
			52				OUT	IN	GND	"							"	2A to 2Y	"	"	"
			53				OUT	GND	IN	"							"	2B to 2Y	"	"	"
			54							"	IN	GND	OUT				"	3A to 3Y	"	"	"
			55							"	GND	IN	OUT				"	3B to 3Y	"	"	"
			56							"				OUT	IN	GND	"	4A to 4Y	"	"	"
			57							"				OUT	GND	IN	"	4B to 4Y	"	"	"
	t <sub>PLH 1</sub>	"	58	IN	GND	OUT				"							"	1A to 1Y	"	45	"
			59	GND	IN	OUT				"							"	1B to 1Y	"	"	"
			60				OUT	IN	GND	"							"	2A to 2Y	"	"	"
			61				OUT	GND	IN	"							"	2B to 2Y	"	"	"
			62							"	IN	GND	OUT				"	3A to 3Y	"	"	"
			63							"	GND	IN	OUT				"	3B to 3Y	"	"	"
			64							"				OUT	IN	GND	"	4A to 4Y	"	"	"
			65							"				OUT	GND	IN	"	4B to 4Y	"	"	"
	t <sub>PHL 2</sub>	"	66	IN	2.7 V	OUT				"							"	1A to 1Y	"	40	"
			67	2.7 V	IN	OUT				"							"	1B to 1Y	"	"	"
			68				OUT	IN	2.7 V	"							"	2A to 2Y	"	"	"
			69				OUT	2.7 V	IN	"							"	2B to 2Y	"	"	"
			70							"	IN	2.7 V	OUT				"	3A to 3Y	"	"	"
			71							"	2.7 V	IN	OUT				"	3B to 3Y	"	"	"
			72							"				OUT	IN	2.7 V	"	4A to 4Y	"	"	"
			73							"				OUT	2.7 V	IN	"	4B to 4Y	"	"	"
	t <sub>PLH 2</sub>	"	74	IN	2.7 V	OUT				"							"	1A to 1Y	"	45	"
			75	2.7 V	IN	OUT				"							"	1B to 1Y	"	"	"
			76				OUT	IN	2.7 V	"							"	2A to 2Y	"	"	"
			77				OUT	2.7 V	IN	"							"	2B to 2Y	"	"	"
			78							"	IN	2.7 V	OUT				"	3A to 3Y	"	"	"
			79							"	2.7 V	IN	OUT				"	3B to 3Y	"	"	"
			80							"				OUT	IN	2.7 V	"	4A to 4Y	"	"	"
			81							"				OUT	2.7 V	IN	"	4B to 4Y	"	"	"

See footnotes at end of device type 03.



TABLE III. Group A inspection for device type 03 – Continued.  
Terminal conditions (pins not designated may be high  $\geq 2.0$  V, low  $\leq 0.7$  V, or open).

Subgroup	Symbol	MIL-STD-883 method	Cases A,B,C,D	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured terminal	Limits		Unit			
			Cases X, 2 1/	2	3	4	6	8	9	10	12	13	14	16	18	19	20							
			Test no.	1A	1B	1Y	2Y	2A	2B	GND	3A	3B	3Y	4Y	4A	4B	V <sub>CC</sub>		Min	Max				
10 T <sub>C</sub> = 125°C	t <sub>PHL 1</sub>	3003 (Fig. 3)	82	IN	GND	OUT				GND								5.0 V	1A to 1Y	2	45	ns		
			83	GND	IN	OUT														1B to 1Y				
			84					OUT	IN	GND											2A to 2Y			
			85					OUT	GND	IN											2B to 2Y			
			86									IN	GND	OUT							3A to 3Y			
			87									GND	IN	OUT							3B to 3Y			
			88												OUT	IN	GND				4A to 4Y			
			89												OUT	GND	IN				4B to 4Y			
	t <sub>PLH 1</sub>		90	IN	GND	OUT														1A to 1Y		56		
			91	GND	IN	OUT															1B to 1Y			
			92					OUT	IN	GND											2A to 2Y			
			93					OUT	GND	IN											2B to 2Y			
			94									IN	GND	OUT							3A to 3Y			
			95									GND	IN	OUT							3B to 3Y			
			96												OUT	IN	GND				4A to 4Y			
			97												OUT	GND	IN				4B to 4Y			
	t <sub>PHL2</sub>		98	IN	2.7 V	OUT														1A to 1Y		45		
			99	2.7 V	IN	OUT															1B to 1Y			
			100					OUT	IN	2.7 V											2A to 2Y			
			101					OUT	2.7 V	IN											2B to 2Y			
			102									IN	2.7 V	OUT							3A to 3Y			
			103									2.7 V	IN	OUT							3B to 3Y			
			104												OUT	IN	2.7 V				4A to 4Y			
			105												OUT	2.7 V	IN				4B to 4Y			
	t <sub>PLH 2</sub>		106	IN	2.7 V	OUT														1A to 1Y		56		
			107	2.7 V	IN	OUT															1B to 1Y			
			108					OUT	IN	2.7 V											2A to 2Y			
			109					OUT	2.7 V	IN											2B to 2Y			
110											IN	2.7 V	OUT							3A to 3Y				
111											2.7 V	IN	OUT							3B to 3Y				
112														OUT	IN	2.7 V				4A to 4Y				
113														OUT	2.7 V	IN				4B to 4Y				
11	Same tests, terminal conditions and limits as for subgroup 10, except T <sub>C</sub> = -55° C.																							

1/ For cases X and 2, pins not referenced are NC.

2/ I<sub>IL</sub> limits in  $\mu$ A shall be as follows:

Parameters	Circuits						
	A	B	C	D	E	F	G
I <sub>IL</sub>	-200/-680	-230/-600	-275/-600	-230/-600	-300/-760	-200/-720	-300/-760

## 5. PACKAGING

5.1 Packaging requirements. For acquisition purposes, the packaging requirements shall be as specified in the contract or order (see 6.2). When actual packaging of materiel is to be performed by DoD personnel, these personnel need to contact the responsible packaging activity to ascertain requisite packaging requirements. Packaging requirements are maintained by the Inventory Control Point's packaging activity within the Military Department of Defense Agency, or within the Military Department's System Command. Packaging data retrieval is available from the managing Military Department's or Defense Agency's automated packaging files, CD-ROM products, or by contacting the responsible packaging activity.

## 6. NOTES

6.1 Intended use. Microcircuits conforming to this specification are intended for original equipment design applications and logistic support of existing equipment.

6.2 Acquisition requirements. Acquisition documents should specify the following:

- a. Title, number, and date of the specification.
- b. Complete part number (see 1.2).
- c. Requirements for delivery of one copy of the quality conformance inspection data pertinent to the device inspection lot to be supplied with each shipment by the device manufacturer, if applicable.
- d. Requirements for certificate of compliance, if applicable.
- e. Requirements for notification of change of product or process to contracting activity in addition to notification to the qualifying activity, if applicable.
- f. Requirements for failure analysis (including required test condition of method 5003 of MIL-STD-883), corrective action, and reporting of results, if applicable.
- g. Requirements for product assurance options.
- h. Requirements for special carriers, lead lengths, or lead forming, if applicable. These requirements should not affect the part number. Unless otherwise specified, these requirements will not apply to direct purchase by or direct shipment to the Government.
- j. Requirements for "JAN" marking.

6.3 Superseding information. The requirements of MIL-M-38510 have been superseded to take advantage of the available Qualified Manufacturer Listing (QML) system provided by MIL-PRF-38535. Previous references to MIL-M-38510 in this document have been replaced by appropriate references to MIL-PRF-38535. All technical requirements now consist of this specification and MIL-PRF-38535. The MIL-M-38510 specification sheet number and PIN have been retained to avoid adversely impacting existing government logistics systems and contractor's parts lists.

6.4 Qualification. With respect to products requiring qualification, awards will be made only for products which are, at the time of award of contract, qualified for inclusion in Qualified Manufacturers List QML-38535 whether or not such products have actually been so listed by that date. The attention of the contractors is called to these requirements, and manufacturers are urged to arrange to have the products that they propose to offer to the Federal Government tested for qualification in order that they may be eligible to be awarded contracts or purchase orders for the products covered by this specification. Information pertaining to qualification of products may be obtained from DSCC-VQ, 3990 E. Broad Street, Columbus, Ohio 43123-1199.

6.5 Abbreviations, symbols, and definitions. The abbreviations, symbols, and definitions used herein are defined in MIL-PRF-38535, MIL-HDBK-1331, and as follows:

GND ..... Ground zero voltage potential  
 $I_{IN}$  ..... Current flowing into an input terminal  
 $V_{IN}$  ..... Voltage level at an input terminal

6.6 Logistic support. Lead materials and finishes (see 3.4) are interchangeable. Unless otherwise specified, microcircuits acquired for Government logistic support will be acquired to device class B (see 1.2.2), lead material and finish A (see 3.4). Longer length leads and lead forming shall not affect the part number.

6.7 Substitutability. The cross-reference information below is presented for the convenience of users. Microcircuits covered by this specification will functionally replace the listed generic-industry type. Generic-industry microcircuit types may not have equivalent operational performance characteristics across military temperature ranges or reliability factors equivalent to MIL-M-38510 device types and may have slight physical variations in relation to case size. The presence of this information shall not be deemed as permitting substitution of generic-industry types for MIL-M-38510 types or as a waiver of any of the provisions of MIL-PRF-38535.

Military device type	Generic-industry type
01	54LS02
02	54LS27
03	54LS266

6.8 Manufacturers' designation. Manufacturers' included in this specification are designated as shown in table IV herein.

TABLE IV. Manufacturers' designation.

Device type	Manufacturer					
	Circuit A Texas Instruments Inc.	Circuit B Signetics Corporation	Circuit C National Semiconductor Corp	Circuit D Raytheon Company	Circuit E Motorola Inc	Circuit F Fairchild Semiconductor
01	A	B	C	G	E	F
02	A	B	C	F	G	E
03	A	B	C	D	E	F

6.9 Changes from previous issue. Asterisks are not used in this revision to identify changes with respect to the previous issue due to the extensiveness of the changes.

Custodians:  
 Army - CR  
 Navy - EC  
 Air Force - 11  
 DLA - CC

Preparing activity:  
 DLA - CC  
 (Project 5962-1947)

Review activities:  
 Army - HD, MI, SM  
 Navy - AS, CG, MC, SH, TD  
 Air Force - 03, 19, 99